

# **MOSFET**

### OptiMOS<sup>™</sup>5 Power-Transistor, 100 V

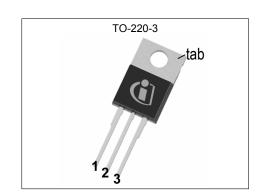
### **Features**

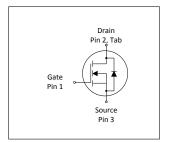
- N-channel, normal level
- $\bullet$  Optimized for FOM  $_{\text{OSS}}$

- Optimized for FOMoss
  Very low on-resistance R<sub>DS(on)</sub>
  175 °C operating temperature
  Pb-free lead plating; RoHS compliant
  Qualified according to JEDEC<sup>1)</sup> for target application
  Ideal for high-frequency switching and synchronous rectification

Table 1 **Key Performance Parameters** 

Table 1 Roy 1 of formation 1 aramotore							
Parameter	Value	Unit					
<b>V</b> <sub>DS</sub>	100	V					
R <sub>DS(on),max</sub>	2.3	mΩ					
$I_{D}$	120	A					











Type / Ordering Code	Package	Marking	Related Links
IPP023N10N5	PG-TO220-3	023N10N5	-

# OptiMOS<sup>™</sup>5 Power-Transistor, 100 V IPP023N10N5



# **Table of Contents**

Description	1
Maximum ratings	3
Thermal characteristics	3
Electrical characteristics	4
Electrical characteristics diagrams	6
Package Outlines	0
Revision History	1
Trademarks 1	1
Disclaimer	1

# OptiMOS<sup>™</sup>5 Power-Transistor, 100 V iPP023N10N5



# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 **Maximum ratings** 

Davamatav	Sumb al	Values			11	Note / Tool Operation	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current	I <sub>D</sub>	-	-	120 120	А	T <sub>C</sub> =25 °C T <sub>C</sub> =100 °C	
Pulsed drain current <sup>1)</sup>	I <sub>D,pulse</sub>	-	-	480	Α	T <sub>C</sub> =25 °C	
Avalanche energy, single pulse	<b>E</b> AS	-	-	1166	mJ	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$	
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-	
Power dissipation	P <sub>tot</sub>	-	-	375	W	T <sub>C</sub> =25 °C	
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	IEC climatic category; DIN IEC 68-1: 55/175/56	

#### Thermal characteristics 2

**Thermal characteristics** Table 3

Dovomotov	Cumbal	Values			l lmi4	Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	0.3	0.4	K/W	-	
Thermal resistance, junction - ambient, minimal footprint	$R_{thJA}$	_	-	62	K/W	-	
Thermal resistance, junction - ambient, 6 cm² cooling area²)	R <sub>thJA</sub>	-	-	40	K/W	-	
Soldering temperature, wave and reflow soldering are allowed	$T_{sold}$	-	-	260	°C	reflow MSL1	

 $<sup>^{1)}</sup>$  see Diagram 3  $^{2)}$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.



### 3 Electrical characteristics

**Table 4** Static characteristics

Daniel and a second a second and a second an	0	Values					
Parameter	Symbol	Min.	Тур. Мах.		Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	100	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	2.2	3	3.8	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =270 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	7 100	μΑ	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	$I_{\mathrm{GSS}}$	-	1	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	2.0 2.3	2.3 2.8	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A V <sub>GS</sub> =6 V, I <sub>D</sub> =50 A	
Gate resistance <sup>1)</sup>	R <sub>G</sub>	-	1.3	2.0	Ω	-	
Transconductance	<b>g</b> fs	124	248	-	S	$ V_{\rm DS}  > 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 100 \text{ A}$	

Table 5 Dynamic characteristics<sup>1)</sup>

Davamatav	Syran had	Values				
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Input capacitance	C <sub>iss</sub>	-	12000	15600	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=1 MHz
Output capacitance	Coss	-	1810	2353	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, <i>f</i> =1 MHz
Reverse transfer capacitance	C <sub>rss</sub>	-	80	140	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, <i>f</i> =1 MHz
Turn-on delay time	$t_{ m d(on)}$	-	33	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Rise time	t <sub>r</sub>	-	26	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Turn-off delay time	$t_{ m d(off)}$	-	77	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$
Fall time	t <sub>f</sub>	-	29	-	ns	$V_{\rm DD}$ =50 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =100 A, $R_{\rm G,ext}$ =1.6 $\Omega$

Table 6 Gate charge characteristics<sup>2)</sup>

Parameter	Cumbal	Values			Unit	Note / Test Condition	
Farameter	Symbol	Min.	Тур.	Max.	Ullit	Note / Test Condition	
Gate to source charge	Q <sub>gs</sub>	-	54	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate to drain charge <sup>1)</sup>	Q <sub>gd</sub>	-	34	58	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Switching charge	Q <sub>sw</sub>	-	52	-	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate charge total <sup>1)</sup>	Qg	-	168	210	nC	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Gate plateau voltage	V <sub>plateau</sub>	-	4.5	-	V	$V_{DD}$ =50 V, $I_{D}$ =100 A, $V_{GS}$ =0 to 10 V	
Output charge <sup>1)</sup>	Qoss	-	213	283	nC	V <sub>DD</sub> =50 V, V <sub>GS</sub> =0 V	

 $<sup>^{1)}</sup>$  Defined by design. Not subject to production test  $^{2)}$  See "Gate charge waveforms" for parameter definition

# OptiMOS<sup>™</sup>5 Power-Transistor, 100 V IPP023N10N5

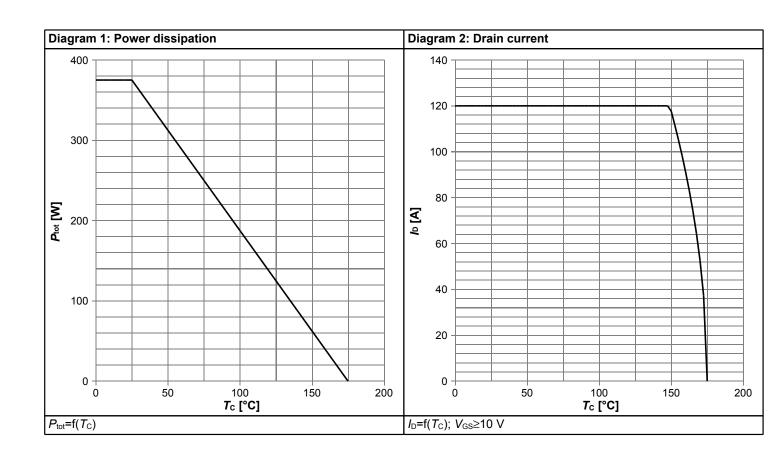


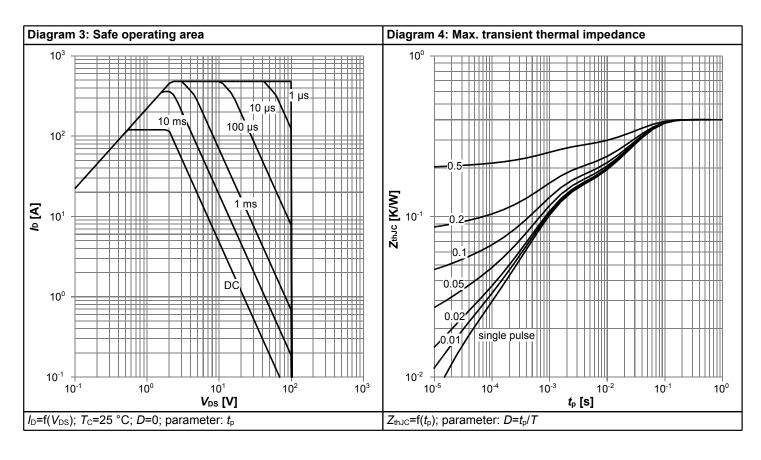
### Table 7 Reverse diode

Dougnation.	Comple of		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continous forward current	Is	-	-	120	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current	I <sub>S,pulse</sub>	-	-	480	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode forward voltage	V <sub>SD</sub>	-	0.9	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	
Reverse recovery time <sup>1)</sup>	t <sub>rr</sub>	-	99	198	ns	$V_R$ =50 V, $I_F$ = $I_S$ , $di_F$ / $dt$ =100 A/ $\mu$ s	
Reverse recovery charge <sup>1)</sup>	Qrr	-	287	574	nC	$V_R$ =50 V, $I_F$ = $I_S$ , $di_F$ / $dt$ =100 A/ $\mu$ s	

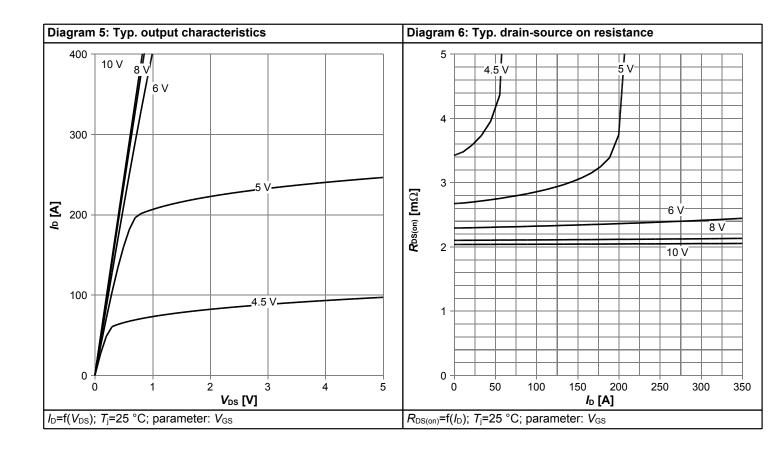


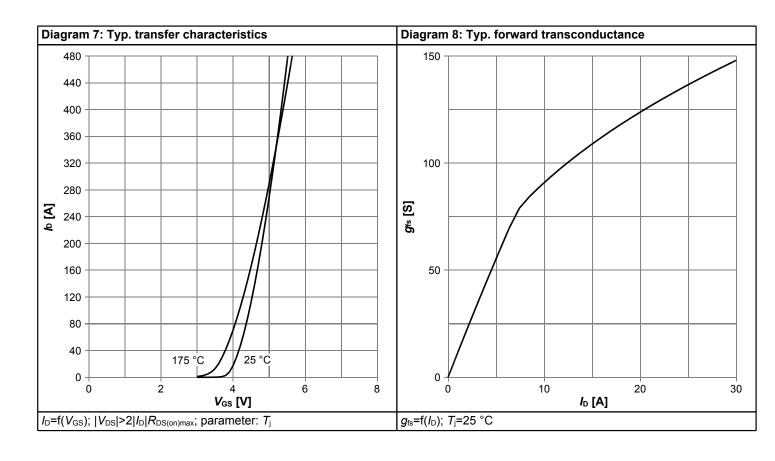
# 4 Electrical characteristics diagrams



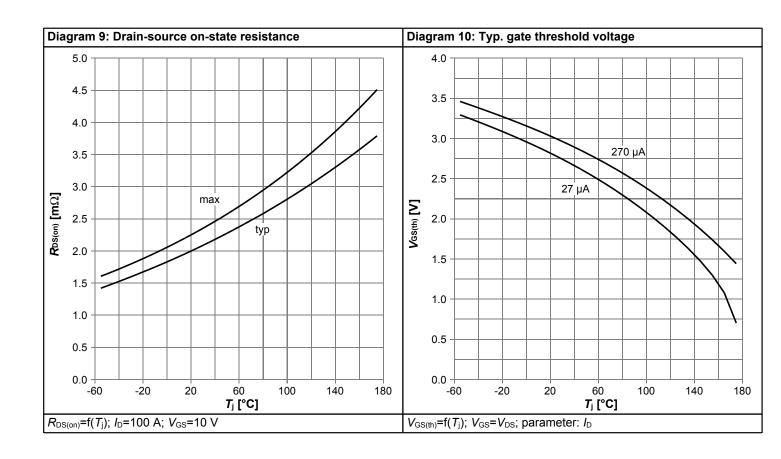


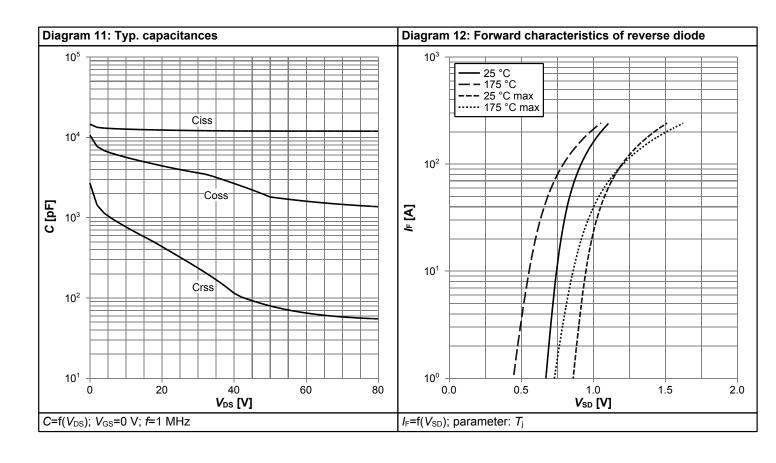




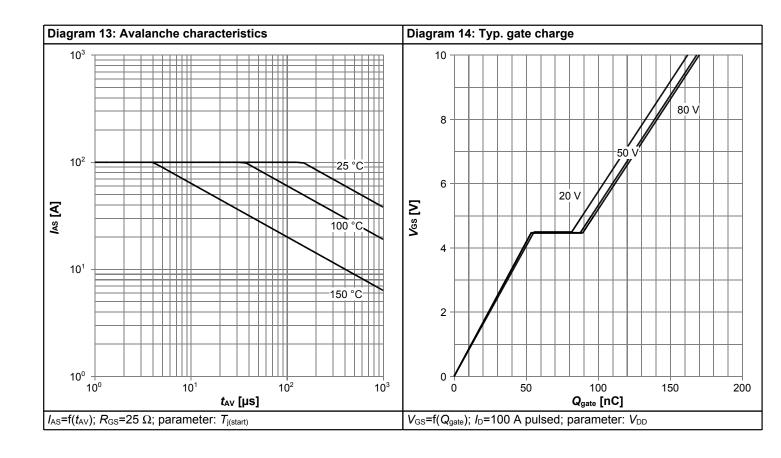


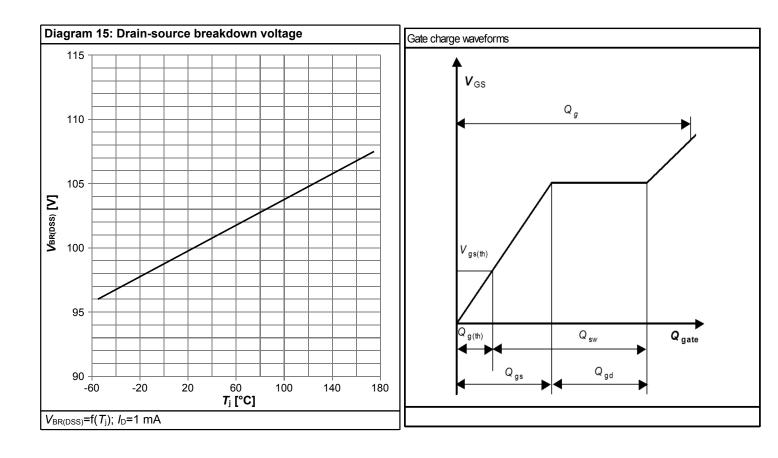






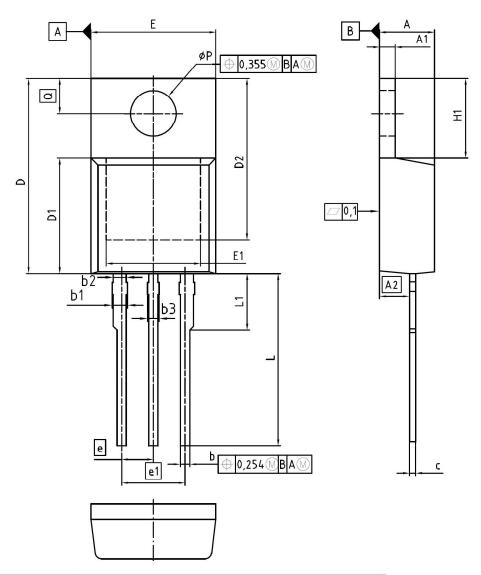








# 5 Package Outlines



DIM	MILLIM	ETERS	INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.30	4.57	0.169	0.180		
A1	1.17	1.40	0.046	0.055		
A2	2.15	2.72	0.085	0.107		
b	0.65	0.86	0.026	0.034		
b1	0.95	1.40	0.037	0.055		
b2	0.95	1.15	0.037	0.045		
b3	0.65	1.15	0.026	0.045		
С	0.33	0.60	0.013	0.024		
D	14.81	15.95	0.583	0.628		
D1	8.51	9.45	0.335	0.372		
D2	12.19	13.10	0.480	0.516		
E	9.70	10.36	0.382	0.408		
E1	6.50	8.60	0.256	0.339		
е	2.5	54	0.100			
e1	5.0	)8	0.200			
N		3	3	3		
H1	5.90	6.90	0.232	0.272		
L	13.00	14.00	0.512	0.551		
L1	-	4.80	=	0.189		
øΡ	3.60	3.89	0.142	0.153		
Q	2.60	3.00	0.102	0.118		

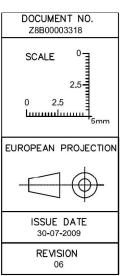


Figure 1 Outline PG-TO220-3, dimensions in mm/inches

# OptiMOS<sup>™</sup>5 Power-Transistor, 100 V IPP023N10N5



### **Revision History**

IPP023N10N5

Revision: 2016-09-23, Rev. 2.3

### **Previous Revision**

Revision	Date	Subjects (major changes since last revision)				
2.1	2014-05-05	Release of Final Version				
2.2	2016-09-07	Update Avalanche Energy				
2.3	2016-09-23	Update Id condition for Avalanche Energy				

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